

# **650V GaN Power Transistor (FET)**

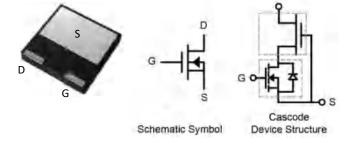
#### **Features**

- Easy to use, compatible with standard gate drivers
- Excellent Q<sub>G</sub> x R<sub>DS(on)</sub> figure of merit (FOM)
- $\bullet \quad \text{Low } Q_{RR}\text{, no free-wheeling diode required}$
- Low switching loss
- RoHS compliant and Halogen-free

Product Summary			
V <sub>DSS</sub> 650 V			
R <sub>DS(on), typ</sub>	240	mΩ	
Q <sub>G, typ</sub>	21.5	nC	
Q <sub>RR, typ</sub>	39	nC	

# **Applications**

- High efficiency power supplies
- High efficiency USB PD adapters
- Other consumer electronics



# **Packaging**

Part Number	Package	Packaging	Base QTY
RX65T300HS2A	DFN 8 x 8	Tape and Reel	2500

## Maximum ratings, at T<sub>C</sub>=25 °C, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T <sub>C</sub> =25°C	9	Α	
I <sub>D</sub>	Continuous drain current @T <sub>C</sub> =100°C	2	6	Α
	Pulsed drain current @T <sub>C</sub> =25°C (puls	e width: 10us)	31	Α
I <sub>DM</sub>	Pulsed drain current @T <sub>C</sub> =150°C (pul	23	Α	
V <sub>DSS</sub>	Drain to source voltage (T <sub>J</sub> = -55°C to	650	V	
V <sub>TDSS</sub>	Transient drain to source voltage <sup>a</sup>	800	V	
V <sub>GSS</sub>	Gate to source voltage	±20	V	
P <sub>D</sub>	Maximum power dissipation @T <sub>C</sub> =25	38	W	
T <sub>C</sub>	On a vating to manage turn	Case	-55 to 150	°C
T <sub>J</sub>	Operating temperature	Junction	-55 to 150	°C
T <sub>S</sub>	Storage temperature	-55 to 150	°C	
T <sub>CSOLD</sub>	Soldering peak temperature	260	°C	



#### **Thermal Resistance**

Symbol	Parameter	Typical	Unit
Rөлс	Junction-to-case	3.3	°C/W
Rоја	Junction-to-ambient <sup>b</sup>	50	°C/W

#### Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- b. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)



## Electrical Parameters, at T<sub>J</sub>=25 °C, unless otherwise specified

Symbol	Min	Тур	Max	Unit	Test Conditions
Forward Chara	cteristics			I	
$V_{DSS-MAX}$	650	-	-	V	V <sub>GS</sub> =0V
$V_{GS(th)}$	1.2	1.6	2.0	V	$V_{DS}=V_{GS}$ , $I_D=500\mu A$
D C	190	240	312	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25°C
$R_{DS(on)}$	-	500	-	11122	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150°C
I <sub>DSS</sub>	-	8	20	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
אטי	-	50	-	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
I <sub>GSS</sub>	-	-	150	nA	V <sub>GS</sub> =20V
'655	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	500	-	pF	
C <sub>OSS</sub>	-	18	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =650V, f=1MHz
C <sub>RSS</sub>	-	2	-	pF	
C <sub>O(er)</sub>	-	25	-	pF	V 9V V 9 559V
C <sub>O(tr)</sub>	-	45	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 650V
$Q_G$	-	21.5	-		
$Q_{GS}$	-	3	-	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =5.5A
$Q_{GD}$	-	3.5	-		
t <sub>D(on)</sub>	-	20	-		
t <sub>R</sub>	-	7	-		V 400V V 0 13V L 3A B 300
t <sub>D(off)</sub>	-	80	-	ns	$V_{DS}$ =400V, $V_{GS}$ =0 - 12V, $I_{D}$ =3A, $R_{G}$ =30 $\Omega$
t <sub>F</sub>	-	6	-		
Reverse Charac	cteristics				
	-	1.2	-		V <sub>GS</sub> =0V, I <sub>S</sub> =2A, T <sub>J</sub> =25°C
$V_{SD}$	-	1.7	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25°C
	-	2	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =150°C
t <sub>RR</sub>	-	12	-	ns	
$Q_{RR}$	-	39	-	nC	$I_S=3A$ , $V_{GS}=0V$ , $d_i/d_t=1000A/us$ , $V_{DD}=400V$

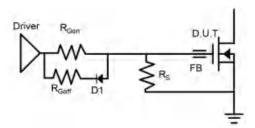
#### Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



## **Circuit Implementation**

Mostly used in flyback, forward and push-pull converters



**Recommended Single Ended Drive Circuit** 

Recommended gate drive: (0 V, 12 V) with R $_{\rm Gon}$  = 300 - 500  $\Omega$ , R $_{\rm Goff}$  =10  $\Omega$ 

Gate	Gate	Gate	Gate Source	Gate
Ferrite Bead	Resistance	Resistance	Resistance	Diode
(FB)	(R <sub>Gon</sub> )	(R <sub>Goff</sub> )	(R <sub>s</sub> )	(D1)
300 - 600 Ω@100 MHz	300 - 500 $\Omega$	10 Ω	10 kΩ	1N4148



#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

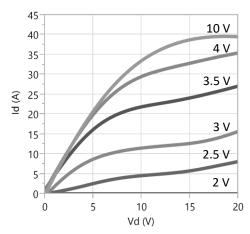
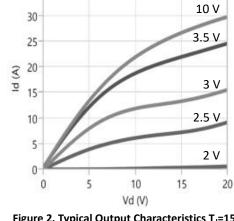


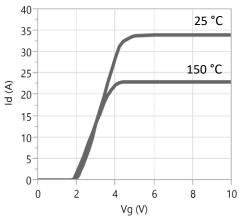
Figure 1. Typical Output Characteristics T<sub>J</sub>=25°C



35

Figure 2. Typical Output Characteristics T<sub>J</sub>=150°C Parameter: V<sub>GS</sub>

Parameter: V<sub>GS</sub>



**Figure 3. Typical Transfer Characteristics** 

3.0 2.5 Normalized Rds(on) 2.0 1.5 1.0 0.5 0.0 0 25 100 125 150 175 50 75 Tj (°C)

Figure 4. Normalized On-resistance

I<sub>D</sub>=4A, V<sub>GS</sub>=8V

V<sub>DS</sub>=10V, Parameter: T<sub>J</sub>

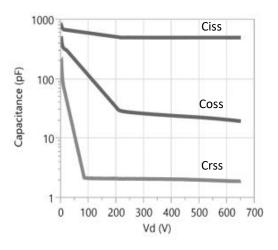


Figure 5. Typical Capacitance

6 5 Eoss (uJ) 4 3 2 0 100 200 500 600 700 300 400 Vd (V)

Figure 6. Typical Coss Stored Energy

V<sub>GS</sub>=0V, f=1MHZ



## Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

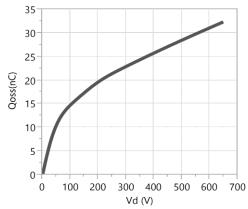


Figure 7. Typical Qoss

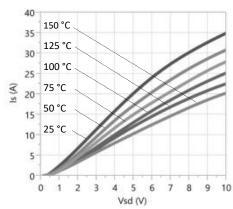


Figure 8. Forward Characteristic of Rev. Diode

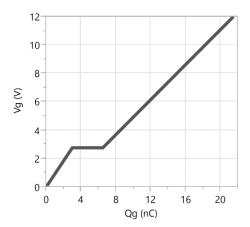


Figure 9. Typical Gate Charge  $I_{DS}{=}5.5A,\,V_{DS}{=}400V$ 

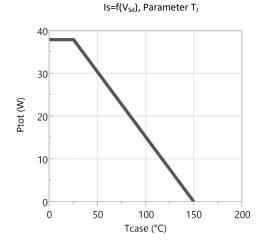


Figure 10. Power Dissipation

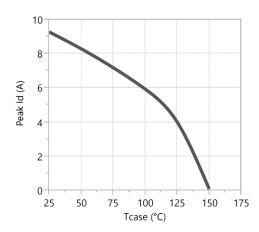


Figure 11. Current Derating



## Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

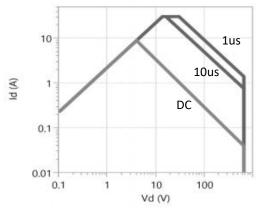


Figure 12. Safe Operating Area  $T_c$ =25°C

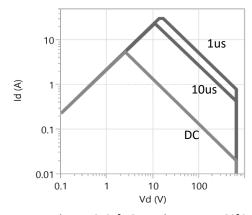


Figure 13. Safe Operating Area T<sub>C</sub>=80°C

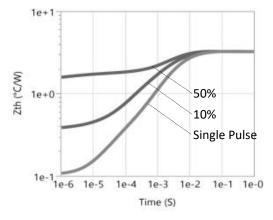


Figure 14. Transient Thermal Resistance



#### **Test Circuits and Waveforms**

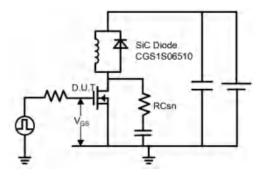


Figure 15. Switching Time Test Circuit

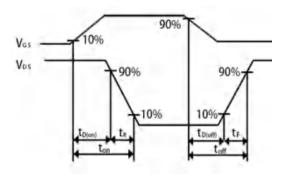


Figure 16. Switching Time Waveform

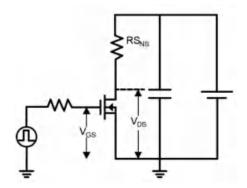


Figure 17. Dynamic R<sub>DS(on)</sub> Test Circuit

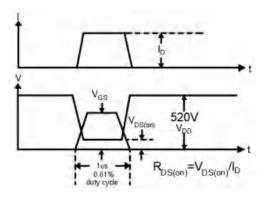


Figure 18. Dynamic R<sub>DS(on)</sub> Waveform

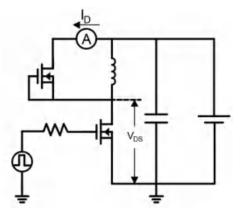


Figure 19. Diode Characteristic Test Circuits

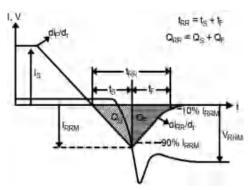


Figure 20. Diode Recovery Waveform



#### **Design Considerations**

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

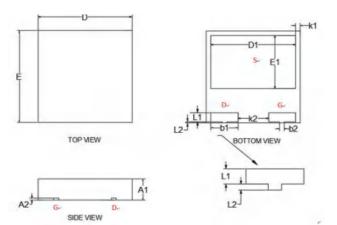
Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

#### When Evaluating Runxin Micro's GaN Devices:

DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of DFN 8*8mm packages	Use long traces in drive circuit, or long lead length of
when installing them to PCB	the devices



## **Package Outline**

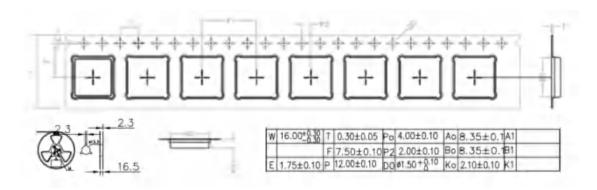


## DFN 8 x 8mm (HS) Package

Cumbial.	Dimensions in Millimeters			
Symbol	MIN	NOM	MAX	
A1	0.850	0.900	0.950	
A2	0.185	0.203	0.230	
D	7,000	8.000	9.000	
E	7.950	8.000	8.050	
1/1	7,050	7.200	7,350	
E1 4.450 K1 0.375		4,600	0.425	
		0.400		
XZ.	2.575	2.600	2,625	
b1.	2.250	2.300	.2.350	
b2	0.375	0,400	0.425	
11	9.700	0.800	0.908	
L2	0.075	0.100	0.125	

## **Tape and Reel Information**

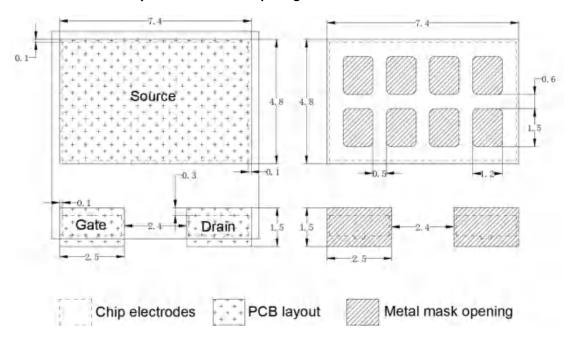
#### Dimensions are shown in millimeters





## **Recommended PCB Layout & Metal mask opening**

#### Dimensions are shown in millimeters



## **Revision History**

Version	Date	Change(s)
1.0	06/24/2022	Release formal datasheet